

High Speed IGBT3 Chip

Features:

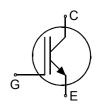
- 650V Trench & Field Stop technology
- high speed switching series third generation
- low V_{CE(sat)}
- low EMI
- low turn-off losses
- positive temperature coefficient
- qualified according to JEDEC for target applications

Recommended for:

 discrete components and modules

Applications:

- uninterruptible power supplies
- welding converters
- converters with high switching frequency



			Package
IGC10T65QE 650	/ 20A	3.19 x 3.21mm ²	sawn on foil

¹⁾ nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

Mechanical Parameters

Die size		3.19 x 3.21			
Emitter pad size		See chip drawing			
Gate pad size		0.361 x 0.513 m			
Area total		10.24			
Thickness		70	μm		
Wafer size		200	mm		
Max.possible chips pe	er wafer	2693			
Passivation frontside		Photoimide			
Pad metal		3200 nm AlSiCu			
Backside metal		Ni Ag –system			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, <500µm			
Reject ink dot size		Ø 0.65mm ; max 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month			
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert ga Humidity <25%RH, Temperature 17°C – 25°C, < 6 month			



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T _{vj} =25 °C	V _{CE}	650	V	
DC collector current, limited by $T_{vj max}$	I _C	1)	А	
Pulsed collector current, t_p limited by $T_{vj max}^{2}$	I _{c,puls}	60	А	
Gate emitter voltage	V _{GE}	±20	V	
Operating junction temperature	T _{vj}	-40 +175	°C	
Short circuit data ^{2) 3)} V_{GE} = 15V, V_{CC} = 400V, T_{vj} = 150°C	t _{sc}	5	μs	

¹⁾ depending on thermal properties of assembly

²⁾ not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V , <i>I</i> _C =2 mA	650			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =20A	1.48	1.95	2.32	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.29mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.2	5.1	5.6	
Zero gate voltage collector current	I _{CES}	V _{CE} =650V , V _{GE} =0V			1	μA
Gate-Emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			150	nA
Integrated gate resistor	r _G			none		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

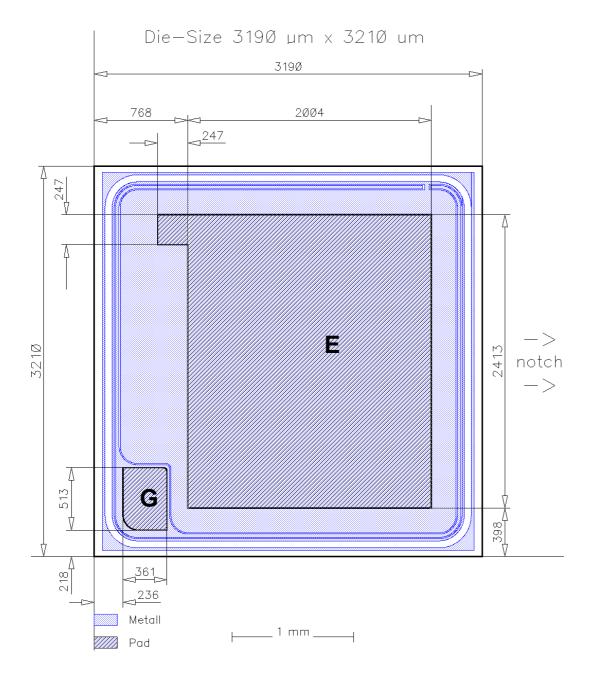
Parameter	Symbol	Conditions	Value			Unit
Falameter			min.	typ.	max.	Unit
Collector Emitter acturation voltage	V	V _{GE} =15V, <i>I</i> _C =20A,		2.5		V
Collector-Emitter saturation voltage	V _{CEsat}	<i>T</i> _{vj} =175 °C				
Input capacitance	Cies	V _{CE} =25V,		1250		
		V _{GE} =0V, <i>f</i> =1MHz				pF
Reverse transfer capacitance	Cres	$T_{\rm vj}$ =25 °C		40		F

Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter **G** = Gate



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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